

Laboratory Multitek Technologies , 201-202, Shri Krishna Complex, Mahesh Apartments, Vasundhara Enclave Main Road, Delhi

Accreditation Standard ISO/IEC 17025: 2005

Certificate Number CC-2139

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Validity 19.11.2018 to 18.11.2020

Last Amended on 21.01.2019

Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ($\pm$)	Remarks
<u>MECHANICAL CALIBRATION</u>				
I.	DIMENSION (BASIC MEASURING INSTRUMENT, GAUGE ETC.)			
1.	Digimatic Indicator / Dial Indicator \$ (Plunger Type) L.C.: 0.001 mm	Up to 25 mm Up to 50 mm	1.2 μ m 6.0 μ m	Using Dial Calibration Tester/ULM
2.	Dial Indicator (Lever Type) \$ L.C.: 0.001 mm	2 mm	1.2 μ m	Using Dial Calibration Tester
3.	Taper Scale\$	Up to 150 mm	5.3 μ m	Using Profile Projector
4.	Feeler Gauge\$	0.01 mm to 1 mm	3.1 μ m	Using ULM
5.	Length Bar/ Long Gauge Blocks\$	25 mm to 625mm	4.5 μ m	Using 2 D Height Master, Optical Flat, Electronic comparator and Gauge Blocks
6.	Profile Projector Charts\$ (Charpy Impact Charts) Radius Chart Angle Chart Linear Scale L.C.: 0.5 μ m	Upto 100 mm Radius 0 to 360° 0 to 215 mm	14.2 μ m 1 min 2.4 μ m	Using Profile Projector

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7.	Profile Projector [#] Magnification Position (Linear) Angle	Up to 100X 0-360 mm 0-360°	0.1% 2.3 μ m 64.3 Sec	Using Glass Scales, Angle Graticule (Protractor)/ Angle Gauge Set
8.	Vision Inspection System/ Universal Measuring Microscope [#] Linear Angular	400mm x 400mm x 100mm 0 to 360°	1.6 μ m 1 min	Using Vision Calibration Gauge, Glass Scale, Gauge Block Set Using Angle Graticule (Protractor)/ Angle Gauges
	Light Microscopes and Reticles [#] Photomicrography Magnification	2000X	0.6%	
	Projection Screen / Video Systems Magnification	2000X	0.6 %	
	Eyepiece Micrometer Scale	25mm	1 μ m	
	Magnification of Eyepiece Image	2000X	0.6%	
	Filar Eyepiece Scale and Drum	100mm	1 μ m	
	Grain Size Comparison Reticle	25mm	1 μ m	
	Ocular Micrometer	20 mm	2.3 μ m	

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10.	Stage Micrometer ^{\$} L.C 1 μ m	1 mm	1.0 μ m	Using Upright Microscope with Filar Micrometer at Magnification 100x and Video Measurement System
	Sine Bar / Sine Table ^{\$} (Grade A and B) Parallelism of Centers w.r.t. bottom	60mm Height	5.6 μ m	Using Lever Type Dial, Surface Plate & Test Mandrel
	Angular Measurement	Up to 45°	13.7 arc Sec	Using Angle Gauge, Gauge Block Set
	Center Distance Between rollers	500mm	4.8 μ m	Using 2D Height Master
	Sine Centre ^{\$} Centre Distance Between Rollers	500 mm	4.1 μ m	
	Parallelism of center axis to bottom contact plane of rollers	500mm	10.0 μ m	
	Angular Measurement	Up to 45°	7.5 arc Sec	
13.	Gauge Block Accessories ^{\$} Holders - Squareness Radius Pieces - Flatness Parallels – Parallelism	300 mm	3.2 μ m	Using Electronic Probe with Comparator Stand Optical Flat, Gauge Block

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14.	Surface Roughness Master / Specimen ^{\$} Ra	10 µm	0.04 µm	Using Surface Roughness Tester
	Ry,(Rmax)	9.3 µm	0.08 µm	
	Rz	1.46 µm	0.08 µm	
15.	Surface Roughness Tester/ Surface Texture Measuring Instrument [#]	Up to 400 µm	0.03 µm	Using Zeiss Three Roughness Reference Specimen, Optical Flat, Step Master
16.	Depth Masters ^{\$} Groove Depth	10 µm	0.04 µm	Using Surface Roughness Tester, Electronic Probe 0.01µm
	Step Height	10 µm	0.61 µm	
17.	Measuring Scale & Tape Calibration Unit [#]	Up to 1000 mm	9.6 µm	Using Gauge Block Set, Long Gauge Block Set
18.	Metric / Steel Scales / Line Standard ^{\$} L.C.0.5 mm	Up to 1000 mm	50 √L µm (Where L is in Meter)	Using Measuring Scale and Tape Calibration Equipment with Optical Viewing and magnifying facility
19.	Measuring Tape / Steel Tape, Woven metallic & glass fiber tape ^{\$} L.C.0.5 mm	Up to 50 meter	50 √L µm (Where L is in Meter)	Using Measuring Scale and Tape Calibration Unit with Optical Viewing with magnifying tension adjustment facility

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20.	Comparator Stand Flatness [#]	300 mm x 300 mm	1.4 μ m	Using Electronic Level, Dial Gauge with Robust stand and distance Piece, Screw Jacks
21.	Vernier Height Gauge / Height Gauge Electronic [#] L.C.: 0.01 mm Measuring Error Parallelism of scribe to base	300 mm 600 mm 1000 mm	6.6 μ m 8.2 μ m 12.0 μ m 4.30 μ m	Using Caliper Checker, Gauge Block Set' Long Gauge Block Set, Surface plate, Granite Square Electronic Comparator
22.	Coating Thickness Meter/Gauge ^{\$} L.C.: 0.1 μ m	Up to 1.5 mm	1.8 μ m	Using Master Thickness Foils
23.	Thickness Foils ^{\$}	0.01 to 2 mm	1.1 μ m	Using Electronic Probe with Comparator Stand, Gauge Block Set 'K' Grade
24.	Bevel Protector / Angle Protector ^{\$} L.C. 1 min • Error of Indication • Straightness of Blade	0° to 180°	2.8 min 7.0 μ m	Using Angle Gauge, Surface Plate, Height Gauge Gauge Block Set Dial Test Indicator

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25.	Combination Sets ^s - Error in Protractor reading - Error in Square Head - Error in Center Head	0° to 180°	2.8 min 2.8 min 2.8 min	Using Profile Projector, Angle Gauge, Surface Plate
26.	Inclinometer / Clinometer ^s L.C.: 1 min	0° to 45°	2.8 min	Using Angle Gauge Block, Electronic Level, Tilting Table, Sine Table, and Gauge Block Set.
27.	Spirit Level / Frame Level ^s L.C.: 0.02 mm / m Bubble Accuracy	± 0.100 mm/m	0.01 mm/m	Using Robust Tilting table, Digital Height Gauge, Digital Dial Indicator, Sine Table, Cylindrical Mandrel, Surface Plate
28.	Angle Plate/Precision Angle Plate [#] - Flatness of working faces - Parallelism of opposite face - Squareness of adjacent Faces	Up to 500 mm	6.0 μ m 6.0 μ m 6.0 μ m	Using Precision Level, Dial Indicator, Surface plate Granite Square, Digital Height Gauge

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29.	Box Angle Plate [#] - Flatness of working face - Parallelism of opposite Faces - Squareness of adjacent faces	Up to 500 mm	6.0 μ m 6.0 μ m 6.0 μ m	Using Precision Level, Dial Indicator, Jacks, Surface Plate, Granite Square, Digital Height Gauge
30.	Granite Square [#] - Parallelism of opposite Face - Squareness of adjacent faces	Up to 500 mm	6.0 μ m 6.0 μ m	Using Precision Level, Dial Indicator, Surface Plate, Granite Square, Digital Height Gauge
31.	Cylindrical Squares ^{\$} Squareness	Up to 600mm	6.0 μ m	Using Gauge Block Set, Surface Plate, Dial Test Indicator, Height Transfer Stand, Granite Square
	Straight Edge [#] Straightness of working face	2000 mm x 200 mm	$2.0\sqrt{\frac{L}{150}}$ μ m L in mm	
	Parallelism of working face	200mm	1.4 μ m	
33.	Surface Plate [#] Flatness deviation	6 m x 6 m	$0.7\sqrt{\frac{(L+W)}{150}}$ μ m L & W in m	Using Electronic Level with Software

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34.	Bench Centre [#] Parallelism Co. Axiality (Alignment of center)	1500 mm	6.3 μ m	Using Test Mandrel, Dial Test Indicator, Height Transfer Stand, Electronic Level
35.	Thread Pitch Gauge ^{\$} Pitch Flank Angle	6.0 mm Up to 60°	2.6 μ m 9.9 min	Using Profile Projector
36.	Test Sieves ^{\$} (Aperture Size)	0.032 to 10 mm >10 mm to 150 mm	3.1 μ m 10 μ m	Using Profile Projector Vernier Caliper
	External Micrometer ^{\$} L.C.: 0.001 mm Micrometer Screw Error	Up to 100 mm Up to 200 mm Up to 500 mm Up to 1000 mm	1.4 μ m 3.3 μ m 4.3 μ m 4.6 μ m	
	• Flatness of Anvils		0.6 μ m	
	• Parallelism of Anvils •		0.6 μ m	
	Internal Micrometer/Stick Micrometer ^{\$} L.C.: 0.01 mm • Two Jaw Micrometer	5mm to 30mm	6.7 μ m	
	• Stick type micrometer	50mm to 300mm	6.9 μ m	

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39.	Micrometer Head ^{\$} L.C.: 0.0001 mm Deviation of Traverse	Up to 100 mm	1.1 μ m	Using Electronic Probe , Gauge Block Set, Optical Flat
40.	Dial Thickness Gauge ^{\$} L.C.:0.001 mm	0 to 25 mm 0 to 10 mm	5.8 μ m 1.0 μ m	Using Gauge Block Set
41.	Caliper Checker/Step Gauge/Check Master ^{\$} Pitch Block Accuracy (Length)	Up to 1000 mm	12.4 μ m	Using Gauge Block Set 'K' Grade, Long Gauge Block, Electronic Probe, Surface Plate / Vertical Single Axis Measuring Machine
42.	Depth Micrometer ^{\$} L.C.: 0.001 mm	100 mm 300mm	1.1 μ m 2.7 μ m	Using Gauge Block Set, Long Gauge Block Set
43.	Vernier Caliper / Dial Caliper/ Digimatic Caliper ^{\$} L.C.: 0.01 mm	300 mm 600 mm 1000 mm	6.6 μ m 8.2 μ m 14.5 μ m	Using Gauge Block Set, Caliper Checker, Long Gauge Block, Digital Micrometer, Gauge block accessories

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44.	Vernier Depth Gauge/Depth Gauge ^{\$} L.C.: 0.01 mm Measuring Error	300 mm 600 mm	8.2 μ m 8.2 μ m	Using Gauge Block Set , Long Gauge Block Set, V Block, Dial Indicator, Surface Plate
45.	Inside Dial Caliper/ Caliper Gauge ^{\$} L.C.: 0.001mm	20 mm to 300 mm	3.50 μ m	Using Gauge block set, Long gauge block, Gauge Block Accessories
46.	Snap Gauge/ Dial Snap Gauge ^{\$} Go, NOGO Gap Size	10mm to 100mm	3.0 μ m	Using Gauge block '0' Grade
47.	Radius Gauge (Concave and Convex Profiles), Radius Fillet Gauge ^{\$}	0.6 mm to 100 mm	14.2 μ m	Using Profile Projector
48.	Angle Gauge ^{\$} Error of Angle	6 sec to 60°	61 sec	Using Sine Bar, Gauge Block Set, Electronic Comparator, Surface Plate
49.	Dial Calibration Tester ^{\$} L.C.: 0.0001 mm Drum accuracy	Up to 25 mm	1.5 μ m	Using Gauge Block Set, Electronic Comparator / Single Axis Measuring Machine

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50.	Bore Gauge ^{\$} L.C 0.001 mm	0 to150mm (up to 3 mm Travel)	4.1µm	Using ULM, Micrometer
51.	(3 Point) Micrometer ^{\$} L.C.: 0.001mm	5 mm to 100 mm	2.70 µm	Using Master Ring Set
52.	Plain Plug Gauge Diameter at Four Positions ^{\$}	1 mm to 100 mm	2.6µm	Using Gauge Block Set - '0' Grade, Electronic Comparator / ULM
	V Block [#] Parallelism (Top face, V axis/side face)		6.4 µm	
	Symmetry		6.4 µm	
	Matching tolerance (Height / V Axis)		6.4 µm	
	Squareness		6.4 µm	
54.	Three Wire Set / Thread Measuring ^{\$} Cylinder Diameter	Up to 6 mm	1.4µm	Using ULM
55.	Measuring Pin ^{\$}	0.1 mm to 20 mm	1.2 µm	Using ULM
56.	3D Coordinate Measuring Machine (CMM) [#] Length Measuring Error	1m x 1m x 1m	$3.5\sqrt{(8*\frac{L}{900})}$ µm Where L is in mm	Using Test Sphere, Calibration Ball, Gauge Block Set & Ceramic Step Gauge with Multi Angle Support

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Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ($\pm$)	Remarks
57.	Optical Flat & Optical Parallel ^{\$} Flatness Parallelism between both faces	100 mm	0.25 μ m	Using Monochromatic Light Source, Master Flat, Electronic Comparator, Gauge Block
58.	Gauge Block Set ^{\$}	Up to 25 mm 25 mm to 50 mm 50 mm to 100 mm	0.16 μ m 0.18 μ m 0.20 μ m	Using Gauge Block Comparator & Gauge Block 'K' Grade
59.	Electronic Probe ^{\$} L.C.: 0.01 μ m	Up to 100 mm Up to 50 mm Up to 10mm	2.08 μ m 1.15 μ m 1.10 μ m	Using Gauge Block with Comparator Stand, Optical Flat
60.	Gauge Block Comparator [#] L.C.: 0.01 μ m	0.5 mm to 100 mm	0.15 μ m	Using Reference Gauge Blocks et as per EAL – G21
61.	Micrometer Setting Rod ^{\$} Gauge Length	500 mm	4.30 μ m	Using Gauge Block Set, Surface Plate, Electronic Comparator
62.	Universal Length Measuring Machine [#] L.C.:0.0001 mm	300 mm	0.85 μ m	Using Gauge Block Set, Long Gauge Block, Optical Flat

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63.	Vertical Single Axis Measuring Machine/ 2D Height Master [#] L.C.:0.0001 mm	1000 mm	1.8 μ m	Using Gauge Block Set, Long Gauge Block, Optical Flat
64.	Pistol Caliper ^{\$} L.C.: 0.01mm	Up to 65mm	6.0 μ m	Using Gauge Block Set
65.	Depth Micro Checker ^{\$} L.C.: 0.001mm	Up to 1000 mm	3.5 μ m	Using Gauge Block, Long Gauge Block Set & Electronic Comparator
66.	Engineer's Square/ Tri Square/ Right Angle [#] (Flatness of Block Edge, Flatness of Working Faces of Stock, Parallelism of Blade edge, Squareness of External Square, Squareness of Internal Square)	Up to 500 mm	6.2 μ m	Using Precision Level, Dial Indicator, Surface Plate, Granite Square, Digital Height Gauge, Gauge Block

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67.	Block Square [#] Parallelism between working faces Squareness between working faces	Up to 500 mm	12.8 μ m 6.9 μ m	Using Precision Level, Dial Indicator, Surface Plate, Granite Square, Digital Height Gauge
68.	Gear Tooth Caliper ^{\$} Error External Jaws	Up to 100 mm	6.6 μ m	Using Gauge Block Set
	Engineer's Parallel [#] • Thickness and width variation		1.7 μ m	
	• Parallelism		1.6 μ m	
	• Equality of Pair		2.2 μ m	
	Form Gauge ^{\$} • Linear		2.9 μ m	
	• Radius		2.9 μ m	
	• Angle		1 min	
71.	Plain Ring Gauge ^{\$}	150 mm	1.9 μ m	Using Single Axis Measuring Machine/ULM
	Surface Profiler/ Contour Profiler [#] • Radius error in Master	Up to 100 mm	3.2 μ m	
	• Length	Up to 100 mm	0.2 μ m	
	• Angle	Up to 90°	14.4 Sec	

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73.	Taper Plug Gauge ^{\$}	Up to 100 mm (Taper Length)	14.4 sec	Using Sine Center, Surface Plate, Gauge Block, Electronic Probe L.C. 0.1 μ m
	• Half Taper Angle		1.4 μ m	
	• Roundness		1.4 μ m	
	• Straightness of Taper			
74.	Master Cylinder ^{\$} Roundness of Cylinder	300 mm Height	0.3 μ m	Using Roundness Tester / Form Tester
75.	Roundness Master-Hemi- Sphere ^{\$} Roundness	Upto 100 mm	0.3 μ m	Using Roundness Tester
76.	Roundness Masters – Magnification master / Flick Standard ^{\$}	100 mm	0.3 μ m	Using Roundness Tester
	• Roundness Flick Depth			
	Roundness Tester [#] Spindle Rotational Accuracy		0.1 μ m	
	Pickup Magnification		0.6 μ m	

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78.	Form Tester [#] Spindle Rotational Accuracy	Up to 300 mm (Travel)	0.1 μ m	Using Cylindrical Standards, Glass Hemisphere, Cylindrical Square, Flick Standard
	Pickup magnification		0.3 μ m	
	Straightness Horizontal Arm		0.4 μ m	
	Straightness Vertical Arm		0.4 μ m	
79.	Pie Tape ^{\$} • Calibration of Vernier Scale (Diameter Scale) • Circumferential Scale • Calibration of Main Scale (Diameter Scale)	Up to 1100 mm	$50\sqrt{L}$ μ m (where L is in mm)	Using Profile Projector, Measuring Scale and Tape Calibration Unit with Optical Viewing
80.	Height Master/ Height Setting Micrometer [#] L.C. : 1 μ m (Mean Height Error)	600 mm	5.9 μ m	Using Gauge Block Set 'K' Grade, Long gauge block, Electronic, Probe, Surface Plate / 2D Height Gauge

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81.	Floating Carriage Micrometer / Diameter Measuring Machine [#] L.C.: 0.0001mm - Micrometer Head - Alignment of centers to base - Parallelism of micrometer face to line of centers	Up to 100 mm Centre Distance	1.2 μ m	Using Gauge Block, Electronic Comparator, Test Mandrel, Surface Plate, Cylindrical Masters set, Sylvac Probe
	Test Mandrel ^{\$} (Straight) - Variation in Diameter - Total Runout	500 mm (Length) x 75mm Dia.	5.1 μ m 7.0 μ m	
	Test Mandrel ^{\$} (Taper) - Variation in Diameter - Total Runout - Taper Angle - Straightness of Taper		4.7 μ m 7.0 μ m 5 min 4.8 μ m	
84.	Electronic Level ^{\$} L.C.: 0.001 μ m/m (Error in level reading)	$\pm$ 10 mm/m	3 μ m/m	Using Robust Tilting table with Electronic Probe

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II.	MOBILE FORCE MEASURING SYSTEM			
1.	Push-Pull Gauge ^{\$}	0 to 10 N 10 to 1000 N	1.20 % 0.29 %	Using Newtonian Weights
III.	WEIGHING SCALE AND BALANCE			
1.	Weighing Balances [#] L.C.: 0.1 mg & Coarser L.C.:0.1 g & Coarser L.C.:100 mg & Coarser L.C.:1 g & Coarser L.C.:10 g & Coarser	0 to 200 g 0 to 5 kg 0 to 35 kg 0 to 100 kg 0 to 200 kg	0.2 mg 5 mg 250 mg 2 g 10 g	Using Standard weights of Class E2 as per OIML R – 76-1 Using Standard weights F2 Class as per OIML R – 76-1
IV.	WEIGHTS			
	M1 Class and Coarser ^{\$} (Conventional Mass)	1 mg 2 mg 5 mg 10 mg 20 mg 50 mg 100 mg 200 mg 500 mg 200 g	0.1mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.2 mg	Using Standard Weights of Accuracy Class E2 Using Precision Balances Readability= 0.1 mg based on OIML R 111-1
	M1 Class and Coarser ^{\$} (Conventional Mass)	500 g	0.2 mg	Using Standard Weights of Accuracy Class E2 Using Precision Balances Readability= 10 mg based on OIML R 111-1

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	F2 Class & Coarser ^{\$}	1 g 2 g 5 g 10 g 20 g 50 g 100 g	0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg 0.1 mg	Using Standard Weights of Accuracy Class E2 Using Precision Balances Readability= 0.1 mg based on OIML R 111-1
	M1 Class and Coarser ^{\$} (Conventional Mass)	1 kg 2 kg	0.02 g 0.04 g	Using Standard Weights of Accuracy Class F2 & Precision Balances L. C.: 10 mg based on OIML R 111
		5 kg 10 kg 20 kg	0.1 g 0.1 g 0.3 g	Using Standard Weights of Accuracy Class F2 & Precision Balances L. C.: 0.1 g
		50 kg	4.6 g	Using Standard Weights of Accuracy Class F2 & Precision Balances L. C.: 5 g
V.	ACOUSTIC			
1.	Sound Level Meter ^{\$}	94 dB 114 dB	0.93 dB 1.5 dB	Using Sound Level Calibrator

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VI.	PRESSURE INDICATING DEVICES			
1.	Digital Vacuum Gauge # (Negative Pressure)	(-) 0.9 to 0 bar	0.011 bar	Using Digital Pressure Gauge by Comparison Method as per DKD R-6-1
2.	Pressure Gauge # (Pneumatic)	0 to 35 bar	0.06 bar	Using Digital Pressure Gauge by Comparison Method as per DKD R-6-1
3.	Pressure Gauge # (Hydraulic)	0 bar to 300 bar 300 bar to 1000 bar	0.34 bar 0.82 bar	Using Digital Pressure Gauge by Comparison Method as per DKD R-6-1
VII.	HARDNESS TESTING MACHINE			
1.	Micro Vickers/ Vickers Hardness Testing Machine #	HV 0.2 HV 0.3 HV 1.0 HV 5 HV 10 HV 30	3.3% 3.0% 1.9% 1.9% 1.9% 1.4%	Using Indirect Verification and Standard Blocks as per IS: 1501-2013 Part-2 ASTM E 384 by Indirect Verification
2.	Rockwell Hardness Testing Machine #	HRA HRB HRC HR 15 N	0.45 HRA 0.8 HRB 0.44 HRC 0.73 HR15 N	Using Indirect Verification & Standard Blocks as per IS : 1586 (Part -2) 2018 ASTM E 18 by Indirect Verification

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Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability (±)	Remarks
3.	Brinell Hardness Testing Machine #	HBW 2.5/187.5 HBW 5/750 HBW 10/3000	3.53% 1.2% 1.27%	Using Standard Blocks as per IS : 1500-2013 Part -2 ASTM E 10 by Indirect Verification
4.	BALL (Diameter) \$ (Rockwell, Brinell- Steel/ Carbide)	0.625,2.5,5,10 mm	3.1 µm	Using Micrometer
	Diamond Cone Indentor\$ Angle	120 °±0.35°	0.37°	Using Profile Projector
	Tip Radius	0.2 ±0.015 mm	20 µm	Fillar Microscope
6.	Vicker / Microvickers Indentor Calibration\$ Angel between opposite face	C.C. 136°±0.5°	0.39°	Using Profile Projector (L.C.: 0.1°) as per IS 1501-2013
VIII.	DUROMETER			
1.	Verification & Calibration Of Shore A & D Hardness Tester / Durometer\$	Shore A 0 to 100 Shore D 0 to 100	1.39 Shore A 1.03 Shore D	Using Shore Hardness Calibrator as per ASTM D 2240-15

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Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ($\pm$)	Remarks
IX.	TORQUE GENERATING DEVICES			
1.	Hand Operated Torque Driver ^{\$} (Type-I)	0.18 to 0.9 Nm	1.9%	
	Torque Wrench / Torque Tool ^{\$} - Torque Indicator Type I (A-F)	0.4 to 1000 Nm	2.0 %	
	Torque Setting Type II (A-F)	0.4 to 1000 Nm	1.5 %	
X.	TORQUE MEASURING DEVICES			
1.	Torque meter, Torque Sensor / Transducer with Indicator in Torque Units only ^{\$}	4 Nm to 2000 Nm	0.50 %	Using Standard Newtonian Weight and Beam in Torque calibration Rig
XI.	ACCELERATION AND SPEED			
1.	Tachometer, Tachometer Calibrator, Stroboscope, RPM Meter ^{\$} (Contact) (Non Contact)	20 rpm to 5000 rpm 5000 rpm to 50000 rpm	0.28% 0.28%	Using Digital Tachometer

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Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ($\pm$)	Remarks
<u>THEMAL CALIBRATION</u>				
I.	TEMPERATURE			
1.	RTD / Thermocouple With or Without Indicator/Temperature Controller ^s Transmitter With Sensor ^s Data Logger Temperature Gauge ^s Liquid –In-Glass Thermometer ^s	(-) 80 °C to 50 °C	0.20 °C	Using RTD (PT-100) 4 wire Sensor, 6½ Digital Multimeter & Using Liquid Temperature Bath by Comparison Method
2.	RTD's Thermocouples With & Without Indicator / Temperature Controller [#] Transmitter With Sensor [#] Data Logger Temperature Gauge [#]	50 °C to 200 °C >200 °C to 650 °C 200 °C to 1200 °C	1.1 °C 1. 7°C 2.5 °C	Using RTD (PT-100) 4 wire Sensor, Thermocouple, 6 ½ Digital Multimeter Using Dry Block Calibrator by Comparison Method

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Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ($\pm$)	Remarks
6.	Freezer [#] Oven Environment Chamber Vacuum Oven Cold Room [#]	(-) 80 °C to 50 °C >50 °C to 250 °C	2.4 °C 2.8 °C	Using RTD with Data Logger by max nine Sensor by Special Mapping (Multi Points Calibration)
7.	Muffle Furnace Industrial Furnace Dry Block Furnace [#]	>250°C to 1200°C	4.4 °C	Using Maximum nine K – Type Thermocouple with Data Logger by Mapping (Multipoint Calibration)
II.	SPECIFIC HEAT AND HUMIDITY			
1.	RH Indicator With or Without RH Probe, Thermo Hygrometer Data Logger With RH Sensor [#]	15 % RH to 95% RH @ 25 °C 10 °C to 50 °C @ 50 % RH	1.1% RH 0.70 °C	Using RH Sensor with Indicator & Humidity Generator (Single Point Calibration)
2.	Relative Humidity Indicator Of Environmental Chamber [#]	15 % RH to 95% RH @ 25 °C	3.2%RH	Using RH Indicator with Data Logger & Max nine Sensor by Special Mapping (Multi Points Calibration)

* Measurement Capability is expressed as an uncertainty ($\pm$) at a confidence probability of 95%

§Only in Permanent Laboratory

*Only for Site Calibration

The laboratory is also capable for site calibration however, the uncertainty at site depends on the prevailing actual environmental conditions and master equipment used.